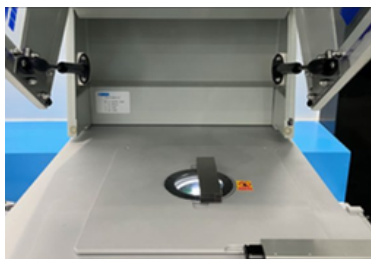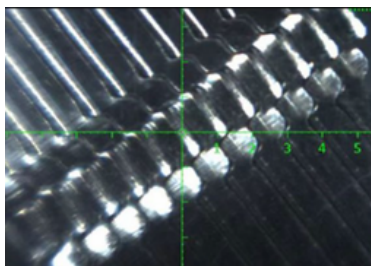# XRF PLATING THICKNESS INSTRUMENT/ ROSH ANALYZER

FEATURES

- According to DIN ISO 3497, DIN 50987, and ASTM B568
- Used for RoHS analysis, electroplating/electrophoretic plating analysis
- Minimum measurement area of 0.2mm² with micro-focus X-ray generator and advanced optical switching focusing system
- Equipped with manual zoom technology, it allows for non-destructive testing of irregular components with depths from 0 to 30mm
- Core EFP algorithm for simultaneous analysis of 23 plating layers, 24 elements
- Equipped with an intelligent vacuum system, it enhances the precision of analysis for platings of light elements, resulting in more stable data

※ The Type C sample chamber is designed for easy sample placement
※ After placing the sample, the test results are available in just a few seconds
※ Nondestructive analysis: No need to destroy the sample
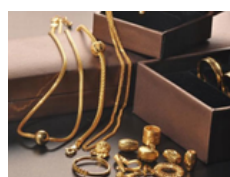
※ High resolution and high magnification color digital image device, picture clear
※ Quickly locate the measurement area through the overall image of the sample
※ With a high-precision micrometer type moving slide, the sample focus can be accurately and quickly aligned in a small area

Electronic components	Permanent magnet material	Precious metals	Chip resistor
Au/Ni/CuSn, Sn/Ni/CuSn...	Ni/Cu/Ni/NdFeB...	18KAu/ Pd/ 925Ag.	Sn/Ni/Ag/ceramic...

TECHNICAL PARAMETERS

MODEL	XTU-4C
Measuring element range	Cl(17)-U(92)
Coating analysis range	Li(3)-U(92)
EFP algorithm	Standard
Analysis software	Simultaneous analysis of 23 coating layers and 24 elements
Different layers of the same Element detection capability	Standard
Software Operation	Humanized closed software automatically determines faults and prompts correction and operation steps to avoid misoperation
X-ray device	Micro-focus enhanced X-ray tube
Signal and reception	Pro-SD processor + PC
Collimator	Φ0.05mm; Φ0.1mm; Φ0.2mm; 0.03*0.2mm; automatic switching of four collimators
Low light focusing technology	The diffusion of the closest ranging spot is less than 10%
Measuring distance	With distance compensation function, the measuring distance can be changed to measure concave and convex special-shaped samples, and the zoom distance can reach 0-30mm
Focusing method	High-sensitivity lens, manual focus
Instrument size	545mm*385mm*430mm
Sample chamber size	Length 430mm×Width 350mm×Height 175mm
Sample stage movement	High precision XY manual slide
Movable range	50mm*50mm
Instrument weight	48KG

Standard delivery	Computer	1pc
	Printer	1pc
	Accessory box	1 set
	12 elements tablet	1pc
	Standard tablet	1 pc